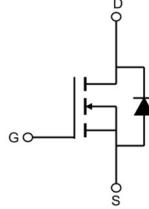


Description

Features <ul style="list-style-type: none"> ● $V_{DS}=650V$, $I_D=15A$ $R_{DS(ON)} < 0.28\Omega$ @ $V_{GS} = 10V$ ● Multi-Epi process SJ-MOSFET ● Smart design in high voltage technology ● Ultra lower on-resistance ● Fast switching ● Ultra low gate charge ● Low reverse recovery charge 	Application <ul style="list-style-type: none"> ● Power factor correction (PFC) ● Switched mode power supplies (SMPS) ● Uninterruptible power supply (UPS) <p style="text-align: center;">100% UIS 100% ΔV_{ds}</p>
 TO-220F	 Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	TUBE (PCS)	Inner Box (PCS)	Per Carton (PCS)
VSM15N65-TF	VSM15N65	TUBE	TO-220F	50	1,000	8,000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		650	V
V_{GSS}	Gate-Source Voltage		± 30	V
I_D	Continuous Drain Current	$T_C = 25^\circ C$	15	A
		$T_C = 100^\circ C$	9.8	
I_{DM}	Pulsed Drain Current ^{note1}		60	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		146	mJ
P_D	Power Dissipation	$T_C = 25^\circ C$	33.2	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		3.76	$^\circ C / W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		80	$^\circ C / W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ C$

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	650	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=650\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$	-	-	1	μA
		$V_{DS}=650\text{V}$, $V_{GS}=0\text{V}$, $T_J=125^\circ\text{C}$	-	-	100	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 30\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	2.0	3.0	4.0	V
$R_{DS(\text{on})}$	Static Drain-Source on-Resistance note3	$V_{GS}=10\text{V}$, $I_D=7.5\text{A}$	-	0.22	0.28	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=50\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	1210	-	pF
C_{oss}	Output Capacitance		-	74	-	pF
C_{rss}	Reverse Transfer Capacitance		-	0.2	-	pF
Q_g	Total Gate Charge	$V_{DS}=480\text{V}$, $I_D=15\text{A}$, $V_{GS}=10\text{V}$	-	24.7	-	nC
Q_{gs}	Gate-Source Charge		-	8.2	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	8.5	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=380\text{V}$, $I_D=7.5\text{A}$, $V_{GS}=10\text{V}$, $R_G=6.8\Omega$	-	14	-	ns
t_r	Turn-on Rise Time		-	8	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	55	-	ns
t_f	Turn-off Fall Time		-	7	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	15	A	
I_{sM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	60	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_s=15\text{A}$	-	-	1.2	V
trr	Reverse Recovery Time	$V_{GS}=0\text{V}$, $I_s=7.5\text{A}$, $di/dt=100\text{A}/\mu\text{s}$	-	240	-	ns
Qrr	Reverse Recovery Charge		-	2	-	μC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J = 25^\circ\text{C}$, $V_{DD} = 50\text{V}$, $V_G = 10\text{V}$, $L = 10\text{mH}$, $I_{AS} = 5.4\text{A}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

Typical Performance Characteristics

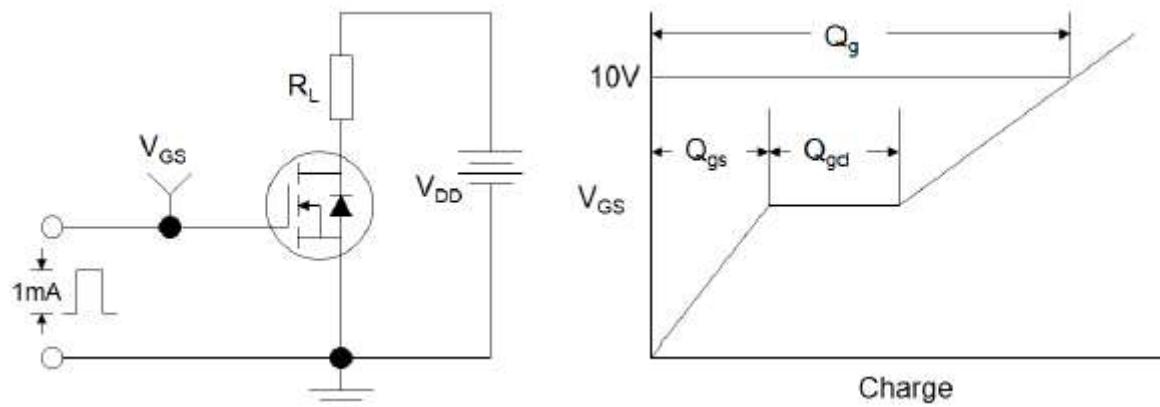


Figure 1: Gate Charge Test Circuit & Waveform

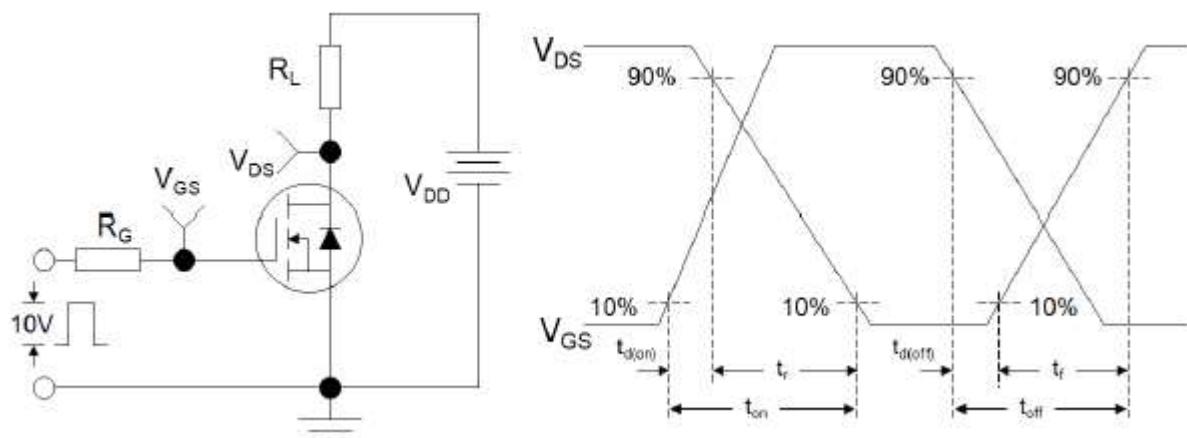


Figure 2: Resistive Switching Test Circuit & Waveforms

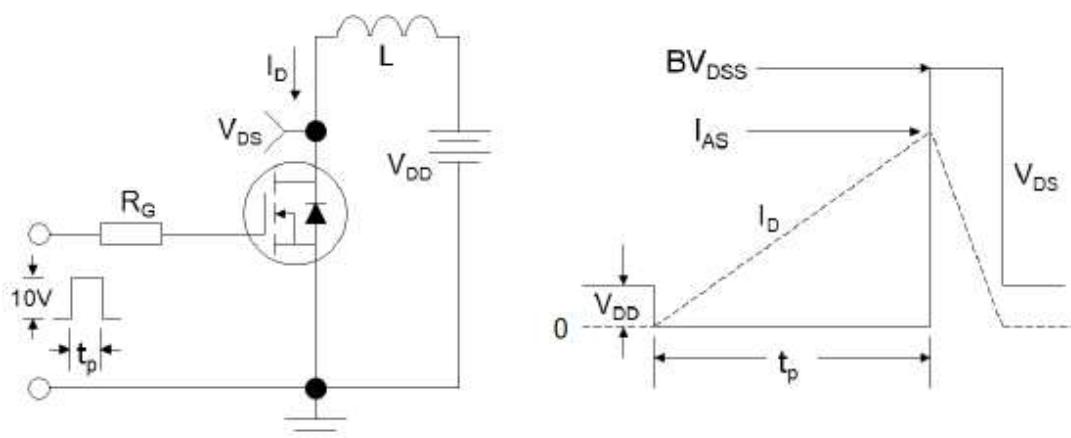


Figure 3: Unclamped Inductive Switching Test Circuit & Waveforms